## Notice of References Cited Application/Control No. 10/553,896 Applicant(s)/Patent Under Reexamination ALBERSHEIM ET AL. Examiner Taeyoon Kim Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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	7	US-			
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## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 3033813 A1	04-2003	WIPO	TEERI et al.	D06M 16/00
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## **NON-PATENT DOCUMENTS**

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